

<b>Notice of References Cited</b>	Application/Control No. 10/670,772		Applicant(s)/Patent Under Reexamination CHOI	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,596,249 A	07-1971	Tierney, William T.	235/380
*	B	US-3,947,666 A	03-1976	Carlson, Robert D.	235/454
*	C	US-4,423,313 A	12-1983	Tanigaki, Shinya	235/379
*	D	US-4,423,318 A	12-1983	Gotou, Kanzen	235/379
*	E	US-4,672,182 A	06-1987	Hirokawa, Katsuhisa	235/436
*	F	US-4,723,269 A	02-1988	Summerlin, Roger N.	379/102.04
*	G	US-4,751,394 A	06-1988	Matsuoka et al.	250/559.29
*	H	US-5,002,062 A	03-1991	Suzuki, Takashi	600/509
*	I	US-5,146,068 A	09-1992	Ugawa et al.	235/441
*	J	US-5,408,633 A	04-1995	Katsumura et al.	711/115
*	K	US-5,484,993 A	01-1996	Seto et al.	235/437
*	L	US-5,553,277 A	09-1996	Hirano et al.	707/104.1
*	M	US-5,832,285 A	11-1998	Shimada, Naoki	713/323

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	Q					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,880,444 A	03-1999	Shibata et al.	235/379
*	B	US-5,877,483 A	03-1999	Bilich et al.	235/382
*	C	US-5,911,080 A	06-1999	Yeom, Yun-pil	713/300
*	D	US-6,009,529 A	12-1999	Park, Geun-Woo	713/320
*	E	US-6,006,335 A	12-1999	Choi et al.	713/310
*	F	US-6,052,742 A	04-2000	Kirinaka et al.	710/10
*	G	US-6,128,744 A	10-2000	Wang, Cheng-Chih	713/300
*	H	US-6,237,848 B1	05-2001	Everett, David	235/380
*	I	US-6,260,111 B1	07-2001	Craig et al.	711/115
*	J	US-2001/0016502 A1	08-2001	Shirai, Kouji	455/558
*	K	US-2001/0035455 A1	11-2001	Davis et al.	235/375
*	L	US-6,325,285 B1	12-2001	Baratelli, Paul J.	235/380
*	M	US-2002/0016913 A1	02-2002	Wheeler et al.	713/170

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0139861 A1	10-2002	MATSUMOTO et al.	235/492
*	B	US-2003/0055686 A1	03-2003	Satoh et al.	705/3
*	C	US-6,590,597 B1	07-2003	Kim, Jin-Hoon	715/866
*	D	US-2003/0126483 A1	07-2003	Huang et al.	713/310
*	E	US-2003/0191960 A1	10-2003	Hung-yi, Yang	713/200
*	F	US-6,670,933 B1	12-2003	Yamazaki, Akihisa	345/1.1
*	G	US-2004/0129776 A1	07-2004	Choi, Young-Hun	235/380
*	H	US-2004/0124238 A1	07-2004	Shimada et al.	235/375
*	I	US-2004/0212735 A1	10-2004	Kitamura, Takashi	348/553
*	J	US-6,856,353 B1	02-2005	Misawa, Takeshi	348/333.07
*	K	US-2005/0101309 A1	05-2005	Croome, Martin	455/418
*	L	US-2005/0205668 A1	09-2005	Sogo, Koji	235/382
*	M	US-2005/0258244 A1	11-2005	Mitchell et al.	235/449

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0279826 A1	12-2005	Merrien, Lionel	235/380
*	B	US-6,993,618 B2	01-2006	Chen et al.	710/305
*	C	US-2006/0041402 A1	02-2006	Baker, Keith	702/189
*	D	US-7,017,811 B2	03-2006	Mitchell et al.	235/449
*	E	US-7,059,520 B1	06-2006	Shtesl, Joel	235/449
*	F	US-2006/0152599 A1	07-2006	Yokonuma et al.	348/231.99
*	G	US-7,107,455 B1	09-2006	Merkin, Cynthia M.	713/182
*	H	US-2007/0019018 A1	01-2007	Wakai, Yoichi	347/014
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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